

1F2
Docket No. 43521-1200

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Tetsushi Yamaguchi et al.

Serial No.: 10/718,068

Filed: November 20, 2003

For: PARTICLE SIZE DISTRIBUTION
ANALYZER

Patent Examiner: Unknown

Group Art Unit: 2877

August 3, 2005

Costa Mesa, California 92626

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment
Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In an attempt to fully comply with the duty of disclosure set forth in 37 C.F.R. § 1.56 and in conformance with 37 C.F.R. §§ 1.97 and 1.98, applicant wishes to bring to the attention of the U.S. Patent Office the following references, which were found during the prosecution of a co-pending Singapore patent application:

WO 01/61313 A3 (MWI, INC)
US 6,404,493 B1 (ALTENDORF)

Copies of the foreign reference and a form PTO-A820 are attached.

The undersigned attorney hereby certifies that each item contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart international application not more than three months prior to filing this statement.

If the Examiner believes that a telephone conference would help further the prosecution of this case, he is respectfully requested to contact the undersigned attorney at the listed telephone number.

I hereby certify that this correspondence is being deposited with the U.S. Postal Service as first class mail in an envelope addressed to: Mail Stop Amendment, Commissioner for Patent, PO Box 1450, Alexandria, VA 22313-1450 on August 3, 2005

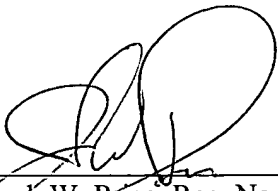
by: Lori Lapidario


Signature

Date of Signature: August 3, 2005

Very truly yours,

SNELL & WILMER LLP



Joseph W. Price, Reg. No. 25,124
600 Anton Boulevard, Suite 1400
Costa Mesa, CA 92626
Tel: 714-427-7420

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional)		Application Number	
				43521-1200		10/718,068	
				Applicant(s)			
				Tetsushi Yamaguchi et al.			
Filing Date				Group Art Unit			
November 20, 2003				2877			

U. S. PATENT DOCUMENTS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		US 6,404,493 B1	6/11/02	Altendorf			

U.S. PATENT APPLICATION PUBLICATIONS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
		WO 01/61313 A3	8/23/01	WIPO			X	

OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>		

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	